

## Supporting Information

### **Nanofilament array embedded tungsten oxide for highly efficient electrochromic supercapacitor electrodes**

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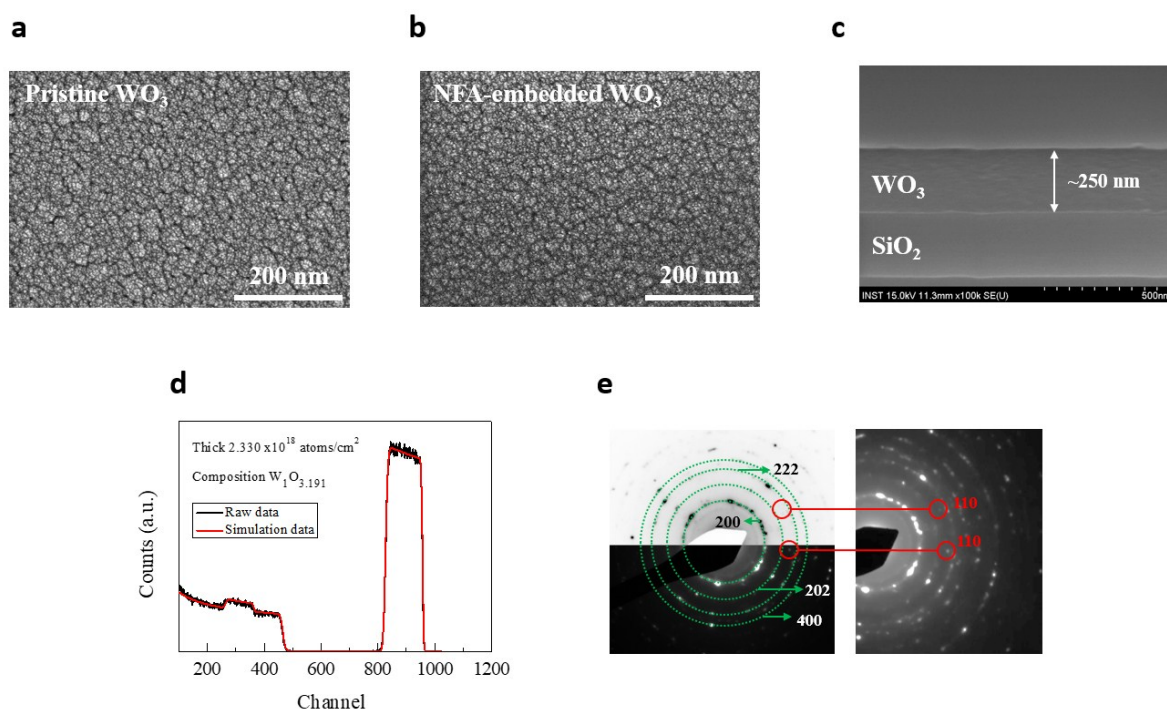
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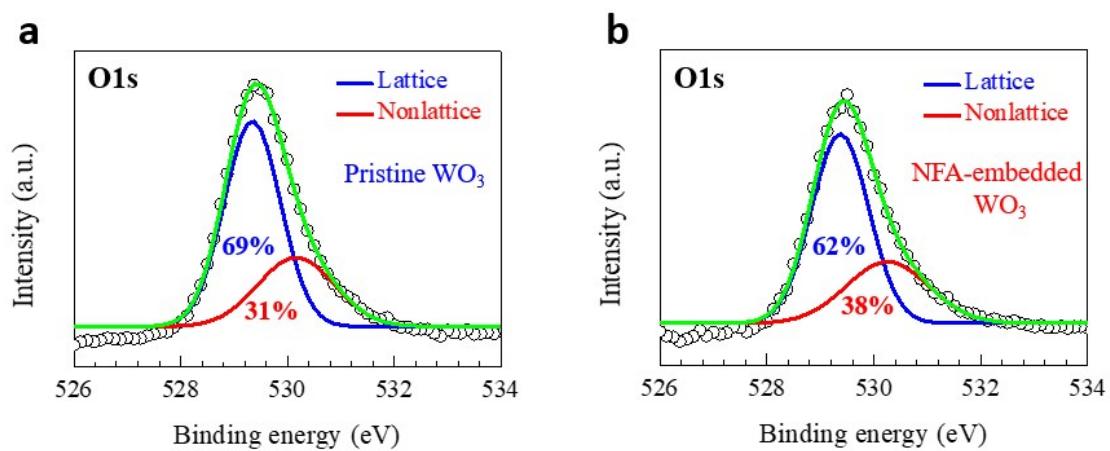
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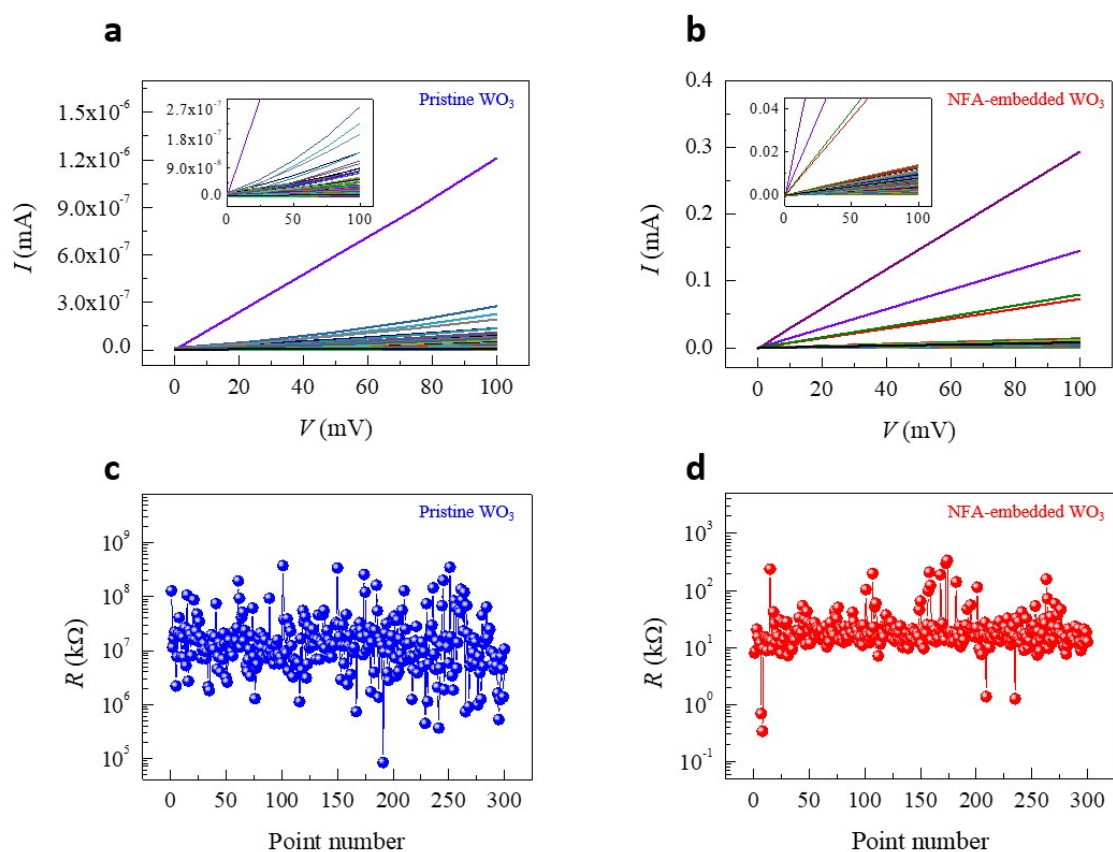
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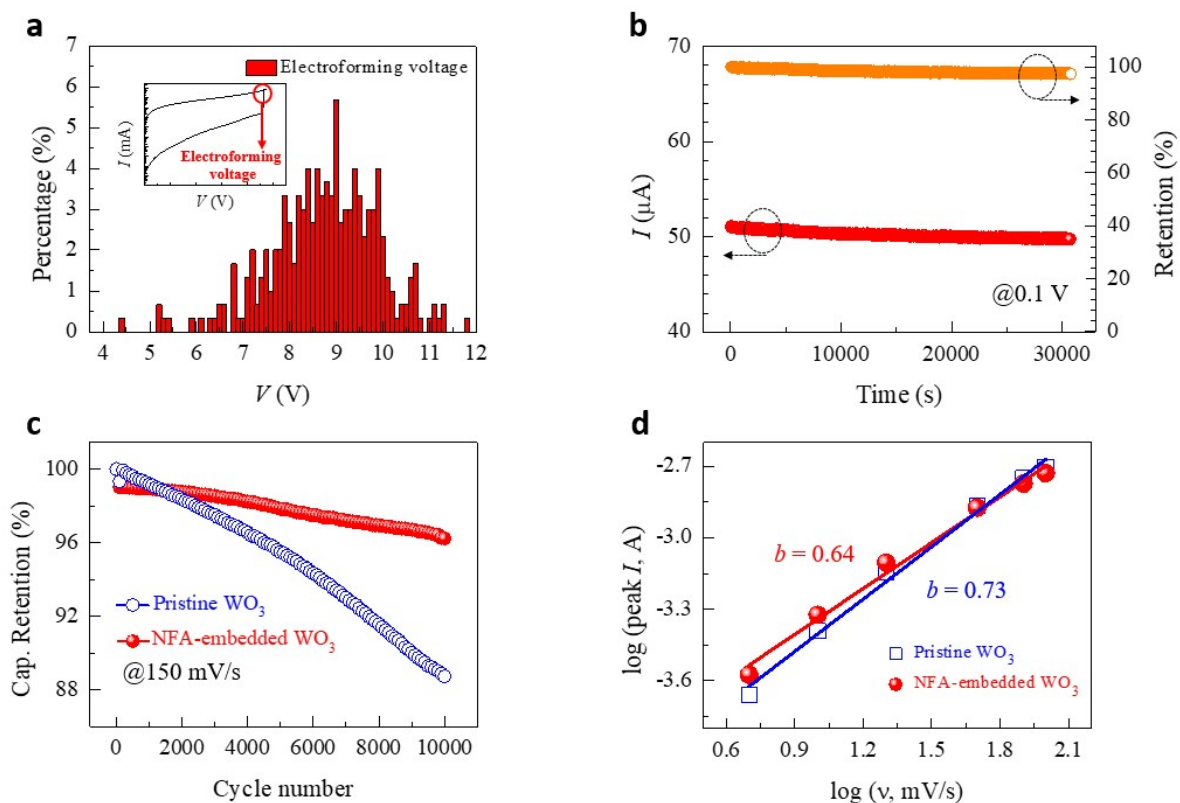
**Fig. S1** Top-view field-emission scanning electron microscopy (FE-SEM) images for (a) the pristine WO<sub>3</sub> and (b) NFA-embedded WO<sub>3</sub> films. (c) Cross-sectional FE-SEM image of the WO<sub>3</sub> film. FE-SEM image showing the thickness of the WO<sub>3</sub> film. (d) Rutherford backscattering spectroscopy (RBS) profiles of the WO<sub>3</sub> film. (e) SAED patterns measured after the electroforming process.



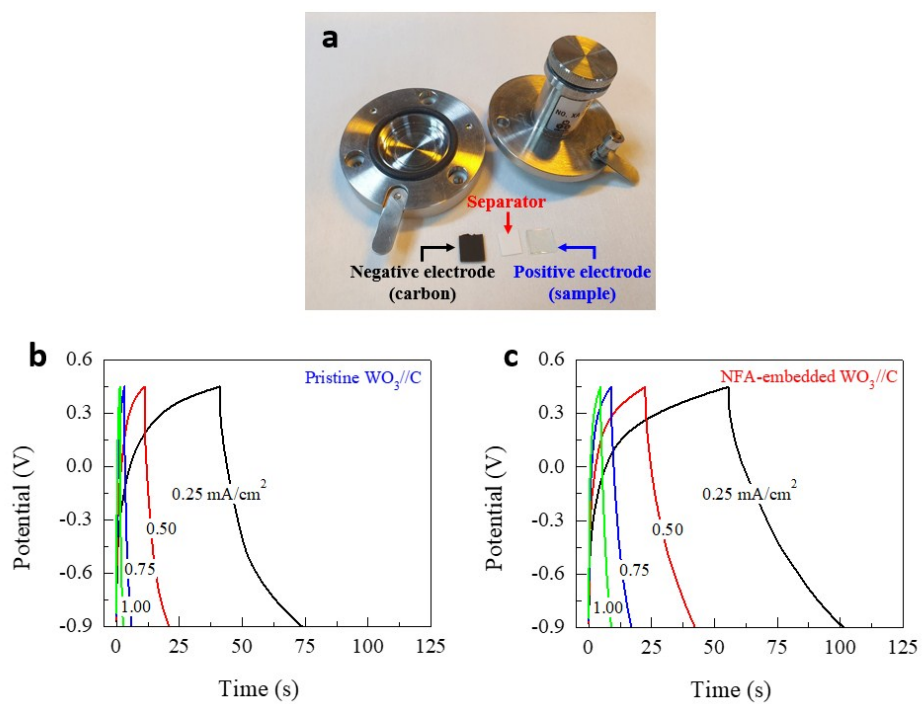
**Fig. S2** XPS spectra for O1s peaks in (a) the pristine WO<sub>3</sub> and (b) NFA-embedded WO<sub>3</sub> films.



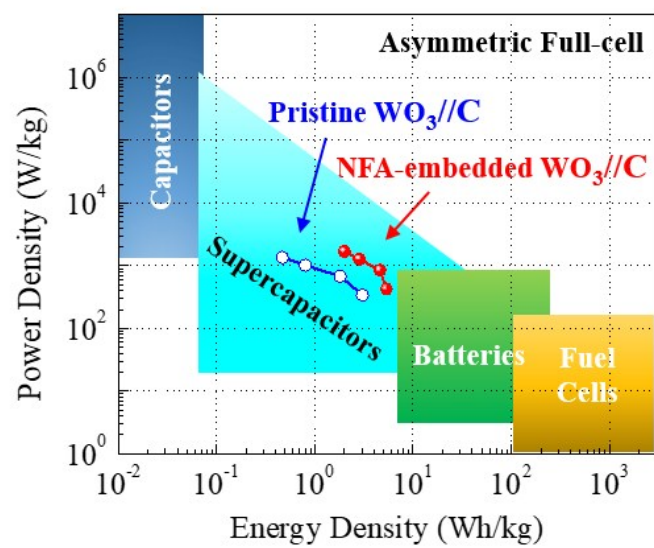
**Fig. S3** Two-probe  $I$ - $V$  characteristics with contacts the WO<sub>3</sub> film and the conducting ITO substrate. (a, b) The measured  $I$ - $V$  curves for the pristine WO<sub>3</sub> and NFA-embedded WO<sub>3</sub> electrodes. The insets show magnified views of the  $I$ - $V$  curves. (c, d) The resistance as a function of the point number at 0.1 V read voltage. The resistance ratio between the pristine WO<sub>3</sub> and NFA-embedded WO<sub>3</sub> electrodes more than 6 orders of magnitude.



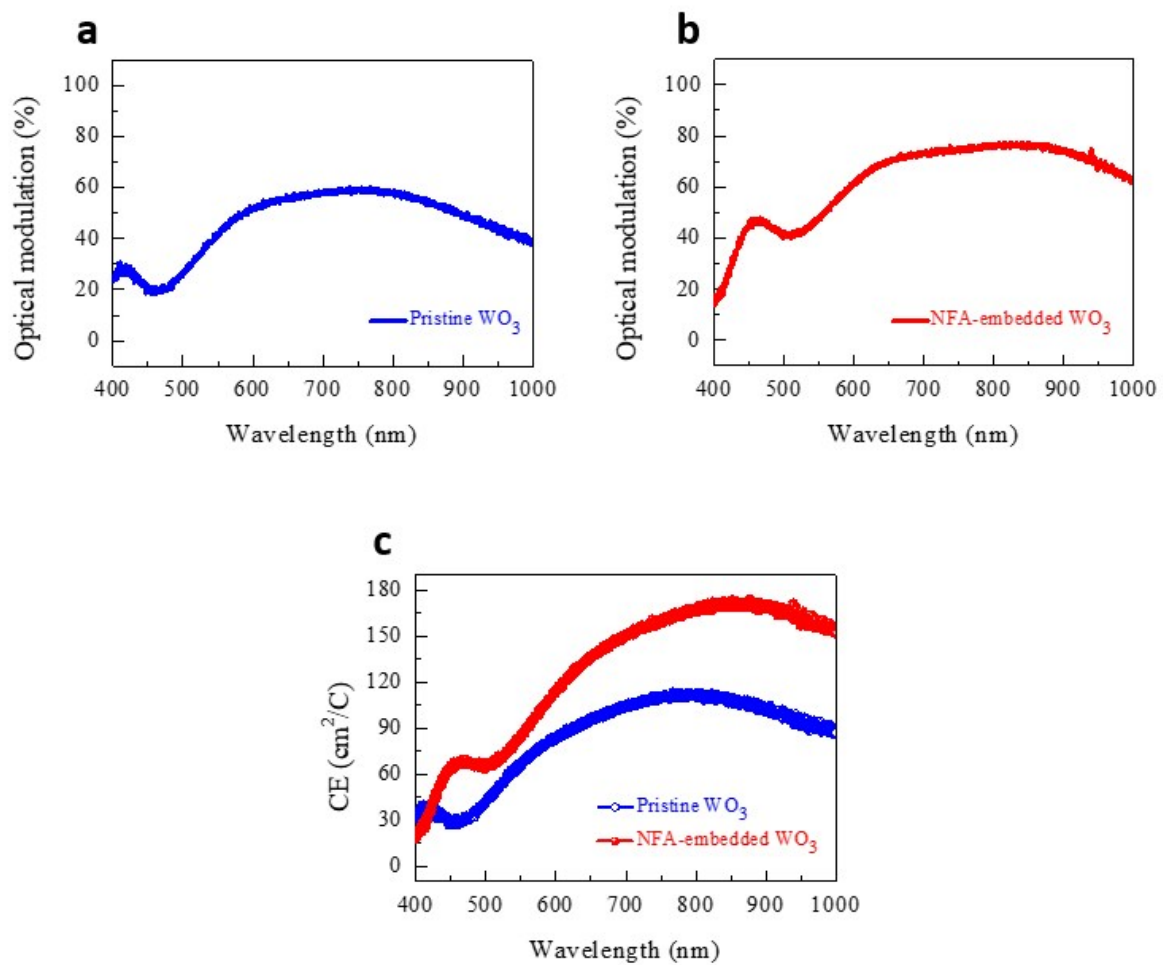
**Fig. S4** (a) Distribution of electroforming voltage for the NFA-embedded  $\text{WO}_3$  electrode. The inset shows the electroforming voltage. (b) Retention characteristic of the NFA-embedded  $\text{WO}_3$  electrode at room temperature and 0.1 V read voltage with almost stable current value. (c) Cycling performance for 10000 cycles at a scan rate of  $150 \text{ mV s}^{-1}$ . (d) Determination of the  $b$ -value at scan rates from 5 to  $100 \text{ mV s}^{-1}$ .



**Fig. S5** (a) Photograph showing the asymmetric supercapacitor. The galvanostatic charge–discharge profiles of (b) the pristine  $\text{WO}_3//\text{C}$  and (c) NFA-embedded  $\text{WO}_3//\text{C}$  asymmetric supercapacitor devices at various current densities.



**Fig. S6** Energy density vs. power density for the pristine  $\text{WO}_3//\text{C}$  and NFA-embedded  $\text{WO}_3//\text{C}$  asymmetric supercapacitors.



**Fig. S7** (a, b) Optical modulation and (c) coloration efficiency for the pristine  $\text{WO}_3$  and NFA-embedded  $\text{WO}_3$  electrodes.



**Table S1** Percentages of different chemical states of W for pristine WO<sub>3</sub> and NFA-embedded WO<sub>3</sub> films.

Chemical states	Percentages of chemical states of W (%)	
	Pristine WO <sub>3</sub>	NFA-embedded WO <sub>3</sub>
W <sup>0</sup> (Metallic W)	0	12.3
W <sup>4+</sup> (WO <sub>2</sub> )	0	33.6
W <sup>5+</sup> (W <sub>2</sub> O <sub>5</sub> )	32.2	10.9
W <sup>6+</sup> (WO <sub>3</sub> )	67.8	43.2